

Search Notes**Application/Control No.**

10/767,725

Examiner

Thomas D. Lee

Applicant(s)/Patent under Reexamination

OGAWA, HIDEHIKO

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
358	1.15, 402, 440	12/8/2005	TDL
379	100.01	12/8/2005	TDL
379	100.08	12/8/2005	TDL
379	100.13	12/8/2005	TDL
379	100.17	12/8/2005	TDL
updated		5/23/2006	TDL
updated		10/16/2006	TDL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference Search Printout		10/16/2006	TDL